IRF740B/IRFS740B



IRF740B/IRFS740B

400V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

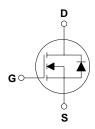
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies and electronic lamp ballasts based on half bridge.

Features

- 10A, 400V, $R_{DS(on)} = 0.54\Omega @V_{GS} = 10 V$ Low gate charge (typical 41 nC)
- Low Crss (typical 35 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		IRF740B	IRFS740B	Units
V _{DSS}	Drain-Source Voltage		400		V
I _D	Drain Current - Continuous (T _C = 25°C)		10	10 *	Α
	- Continuous (T _C = 100°C)		6.3	6.3 *	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	40	40 *	Α
V_{GSS}	Gate-Source Voltage		± 30		V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		450		mJ
I _{AR}	Avalanche Current	(Note 1)	10		А
E _{AR}	Repetitive Avalanche Energy (Note 1)		13.4		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		5.5		V/ns
P_D	Power Dissipation (T _C = 25°C)		134	44	W
	- Derate above 25°C		1.08	0.35	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		ç
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300		°C

^{*} Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	IRF740B	IRFS740B	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.93	2.86	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Symbol	Parameter	Test Conditions	N	/lin	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	4	100			V
ΔBV_{DSS}	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to	25°C		0.4		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 400 V, V _{GS} = 0 V				10	μА
		V _{DS} = 320 V, T _C = 125°C				100	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 5.0 A			0.43	0.54	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 5.0 \text{ A}$	Note 4)		9.6		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1400 150 35	1800 195 45	pF pF pF
	in a Characteristics						
	Ing Characteristics Turn-On Delay Time				20	50	nc
t _{d(on)} t _r	Turn-On Rise Time	$V_{DD} = 200 \text{ V}, I_{D} = 10 \text{ A},$ $R_{G} = 25 \Omega$			80	170	ns ns
t _{d(off)}	Turn-Off Delay Time				125	260	ns
t _f	Turn-Off Fall Time	(N	oto 4 5)		85	180	ns
Q _g	Total Gate Charge	V 220 V I 10 Λ			41	53	nC
Q _{gs}	Gate-Source Charge	$V_{DS} = 320 \text{ V}, I_{D} = 10 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note 4, 5)			7		nC
Q _{qd}	Gate-Drain Charge				17		nC
 Drain-S	Source Diode Characteristics a	nd Maximum Ratings					
I _S	Maximum Continuous Drain-Source Die					10	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current					40	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 10 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 10 \text{ A},$			330		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			3.57		μС

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^{1.} Repetitive Rating : Pulse width limited by maximum junction tempe 2. L = 7.9mH, I_{AS} = 10A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 10A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

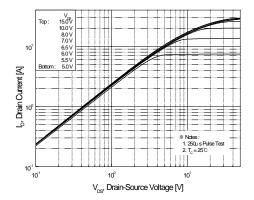


Figure 1. On-Region Characteristics

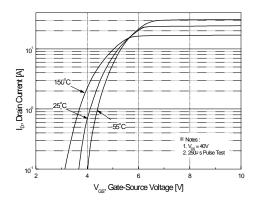


Figure 2. Transfer Characteristics

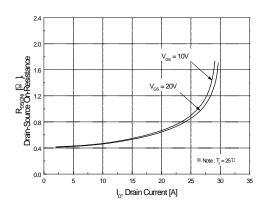


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

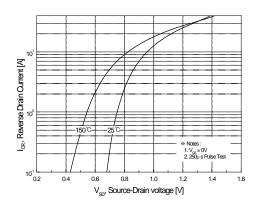


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

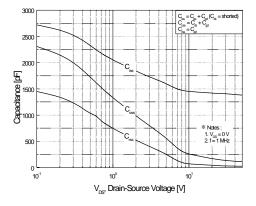


Figure 5. Capacitance Characteristics

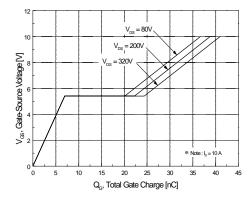


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

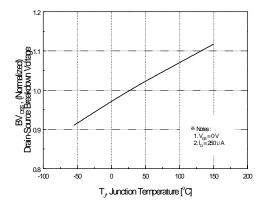


Figure 7. Breakdown Voltage Variation vs Temperature

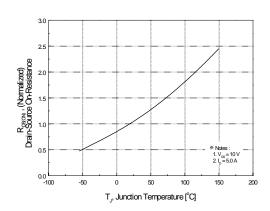


Figure 8. On-Resistance Variation vs Temperature

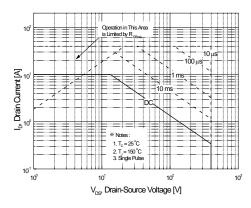


Figure 9-1. Maximum Safe Operating Area for IRF740B

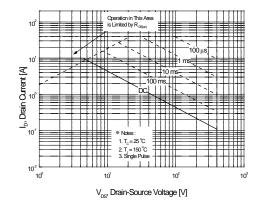


Figure 9-2. Maximum Safe Operating Area for IRFS740B

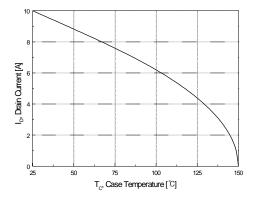


Figure 10. Maximum Drain Current vs Case Temperature

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Typical Characteristics (Continued)

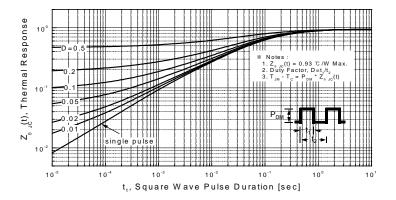


Figure 11-1. Transient Thermal Response Curve for IRF740B

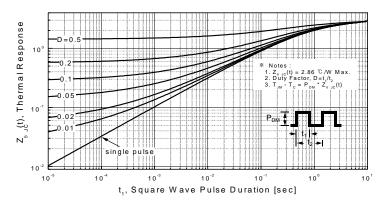
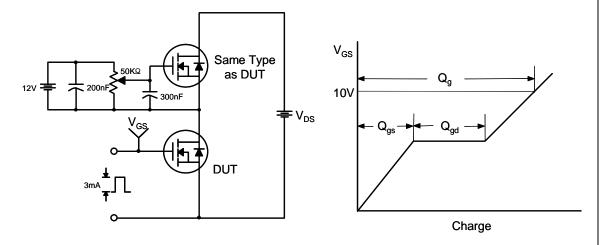


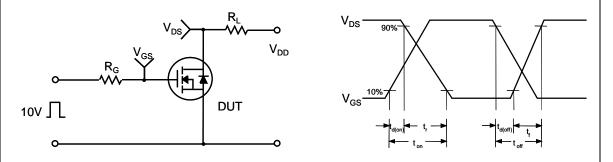
Figure 11-2. Transient Thermal Response Curve for IRFS740B

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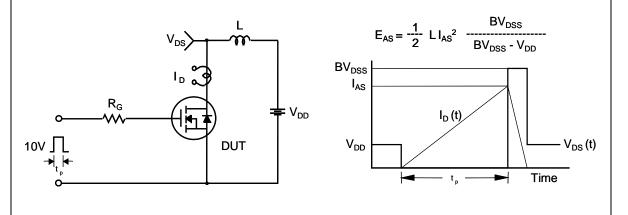
Gate Charge Test Circuit & Waveform



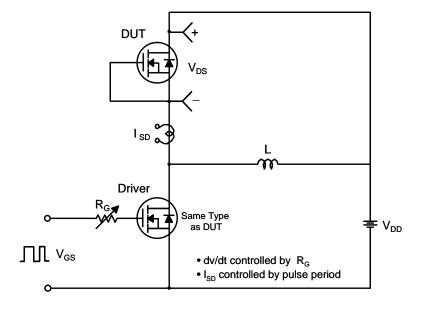
Resistive Switching Test Circuit & Waveforms

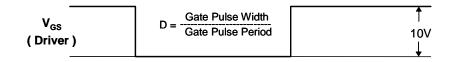


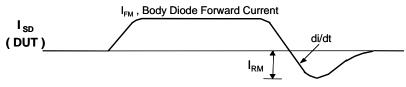
Unclamped Inductive Switching Test Circuit & Waveforms



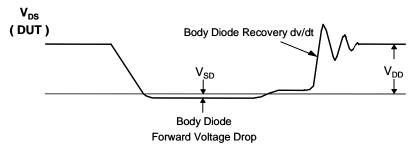
Peak Diode Recovery dv/dt Test Circuit & Waveforms

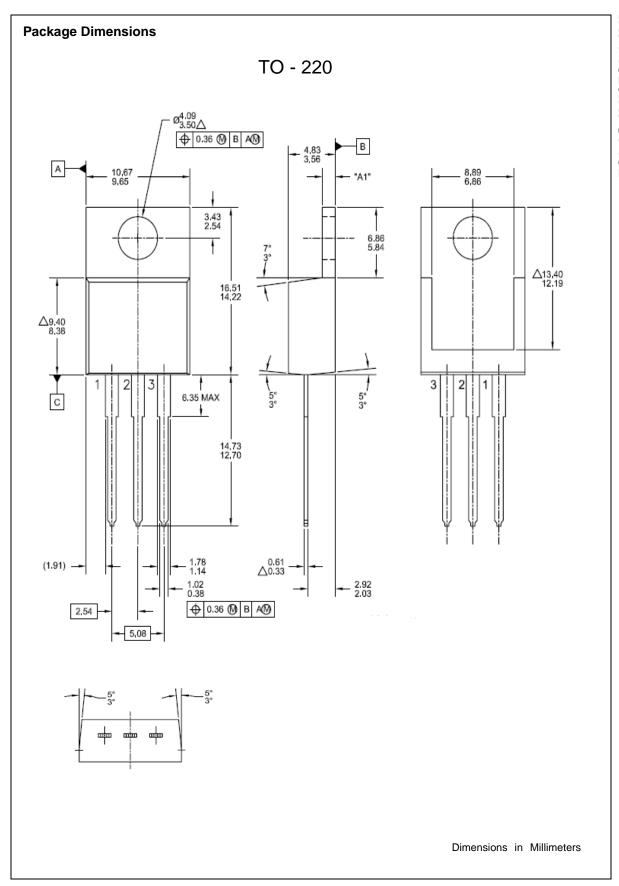


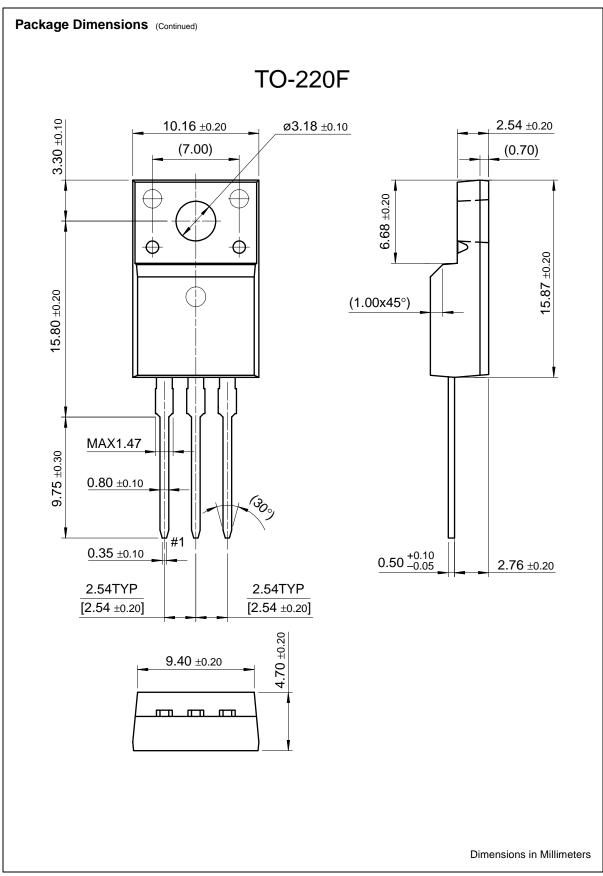




Body Diode Reverse Current







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